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| Form PTO-1449 (REV. 8-83) | | US Dept. of Commerce PATENT & TRADEMARK OFFICE | | ATTY DOCKET NO. 116916 | | APPLICATION NO. New US Application | |
| INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary) | | | | APPLICANTS Takamitsu HIGUCHI et al. FILING DATE August 21, 2003 | | | |
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| EXAMINER <i>gfeland</i> | | | | | DATE CONSIDERED 12/18/04 | | |
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